Electron Beam Induced Current Module

The EBIC module comprises a signal amplifier as well as an intuitive and easy to use control interface. The system is compatible with most commercially available SEM's and FIB's and the amplifier is connected to the microscope’s video input.

Applications
- Non-destructive failure analysis
- Open and short detection in integrated circuits
- Visualization of p-n junctions
- Localization of resistivity changes
- Visualization of grain boundaries in solar cells

Operation modes
- EBIC - electron beam induced current
- EBAC - electron beam absorbed current
- RCI - resistive contrast imaging
- EBIV - electron beam induced voltage
- EBIRCH - electron beam induced resistance change

Technical specifications
- Current measurement limit: 100 fA
- Gain: $10^4$ to $10^{12}$ V/A
- Bandwidth: up to 1 MHz
- Video output: 1 V / 50 Ω (customizable)
- External voltage input
- Large offset range
- AC and DC amplification modes
- Image inversion mode
- Input current compensation
- Selectable bandwidth filter
- Quantitative EBIC/EBAC

Further information
- Contact us at info@kleindiek.com
- Find your local agent at www.kleindiek.com